

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10808971	TEN EYCK ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	John P Lacyk	3735

### **SEARCHED**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
600	21-22, 300-301, 523	6/10/07	JPL
705	3	6/10/07	JPL
340	573.1, 691.6	6/10/07	JPL
Updated	above	1/17/08	JPL

### **SEARCH NOTES**

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>

### **INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>